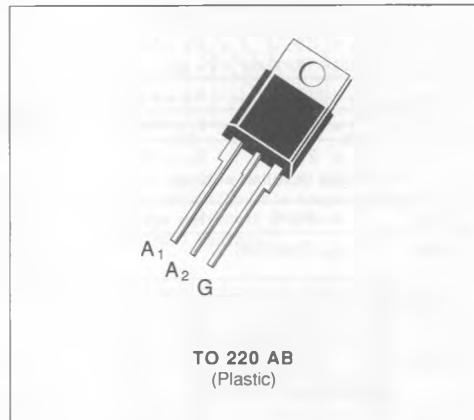


## SENSITIVE GATE TRIACS

- GLASS PASSIVATED CHIP
- IGT SPECIFIED IN FOUR QUADRANTS
- AVAILABLE IN INSULATED VERSION →  
BTA SERIES (INSULATING VOLTAGE  
2500 VRMS) OR IN UNINSULATED VERSION  
→ BTB SERIES
- UL RECOGNIZED FOR BTA SERIES (E81734)



### DESCRIPTION

New range suited for applications such as phase control and static switching.

### ABSOLUTE RATINGS (limiting values)

Symbol	Parameter	Value	Unit
$I_{T(RMS)}$	RMS on-state Current (360° conduction angle)	75 °C	A
$I_{TSM}$	Non Repetitive Surge Peak on-state Current ( $T_j$ initial = 25 °C - Half sine wave)	t = 8.3 ms	A
		t = 10 ms	
$I^2t$	$I^2t$ Value for Fusing	t = 10 ms	$A^2s$
$dI/dt$	Critical Rate of Rise of on-state Current (1)	Repetitive $F = 50$ Hz	$A/\mu s$
		Non Repetitive	
$T_{stg}$ $T_i$	Storage and Operating Junction Temperature Range	- 40 to 150 - 40 to 110	°C °C

Symbol	Parameter	BTA/BTB 04-					Unit
		200T	400T	600T	700T	800T	
$V_{DRM}$	Repetitive Peak off-state Voltage (2)	200	400	600	700	800	V

(1)  $I_c = 50$  mA     $dI/dt = 1$  A/ $\mu s$

(2)  $T_j = 110$  °C.

### THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
$R_{th(j-a)}$	Junction to Ambient	60	°C/W
$R_{th(j-c)}$ DC	Junction to Case for DC	8.7	°C/W
$R_{th(j-c)}$ AC	Junction to Case for 360 ° Conduction Angle ( $F = 50$ Hz)	6.5	°C/W

**GATE CHARACTERISTICS (maximum values)**

$$\begin{array}{ll} P_{GM} = 40 \text{ W } (t_p = 10 \mu\text{s}) & I_{GM} = 4 \text{ A } (t_p = 10 \mu\text{s}) \\ P_{G(AV)} = 1 \text{ W } & V_{GM} = 16 \text{ V } (t_p = 10 \mu\text{s}) \end{array}$$

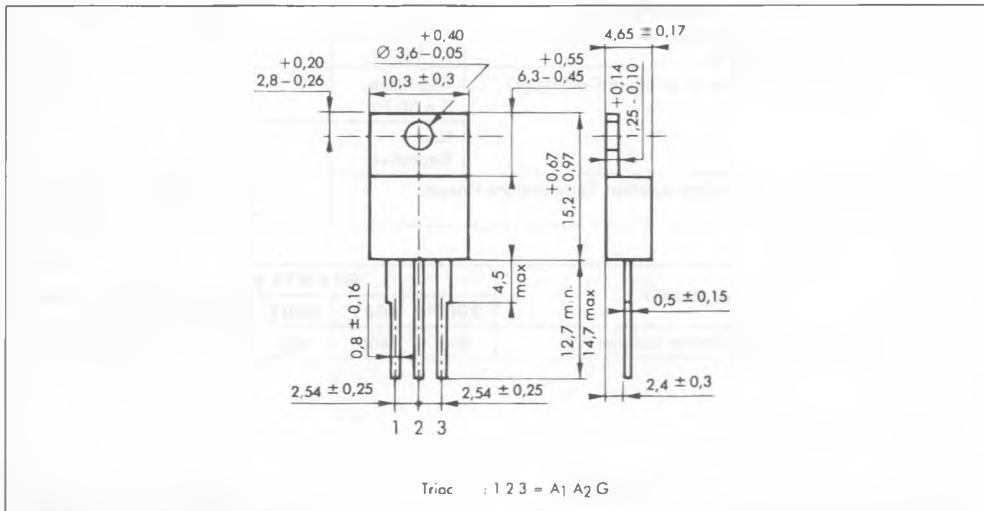
**ELECTRICAL CHARACTERISTICS**

Symbol	Test Conditions	Quadrants	Min.	Typ.	Max.	Unit
I <sub>GT</sub>	T <sub>j</sub> = 25 °C      V <sub>D</sub> = 12 V Pulse Duration > 20 µs	R <sub>L</sub> = 33 Ω	I-II-III-IV		5	mA
V <sub>GT</sub>	T <sub>j</sub> = 25 °C      V <sub>D</sub> = 12 V Pulse Duration > 20 µs	R <sub>L</sub> = 33 Ω	I-II-III-IV		1.5	V
V <sub>GD</sub>	T <sub>j</sub> = 110 °C      V <sub>D</sub> = V <sub>DRM</sub>	R <sub>L</sub> = 3.3 kΩ	I-II-III-IV	0.2		V
I <sub>H*</sub>	T <sub>j</sub> = 25 °C	I <sub>T</sub> = 100 mA	Gate Open		15	mA
I <sub>L</sub>	T <sub>j</sub> = 25 °C      V <sub>D</sub> = 12 V Pulse Duration > 20 µs	I <sub>G</sub> = 10 mA	I-III-IV	15		mA
			II	30		
V <sub>TM</sub> *	T <sub>j</sub> = 25 °C      I <sub>TM</sub> = 5.5 A	t <sub>p</sub> = 10 ms			1.65	V
I <sub>DRM</sub> *	V <sub>DRM</sub> Specified	T <sub>j</sub> = 25 °C			0.01	mA
		T <sub>j</sub> = 110 °C			0.75	
dv/dt*	T <sub>j</sub> = 110 °C      Gate Open Linear Slope up to V <sub>D</sub> = 67 % V <sub>DRM</sub>			10		V/µs
(dv/dt) <sub>c</sub> *	T <sub>C</sub> = 75 °C      V <sub>D</sub> = V <sub>DRM</sub>	I <sub>T</sub> = 5.5 A		1		V/µs
t <sub>gt</sub>	T <sub>j</sub> = 25 °C      V <sub>D</sub> = V <sub>DRM</sub> I <sub>G</sub> = 20 mA	I <sub>T</sub> = 5.5 A	I-II-III-IV	2		µs

\* For either polarity of electrode A<sub>2</sub> voltage with reference to electrode A<sub>1</sub>.

**PACKAGE MECHANICAL DATA**

TO 220 AB Plastic



Cooling method : by conduction (method C)

Marking : type number

Weight : 2 g.

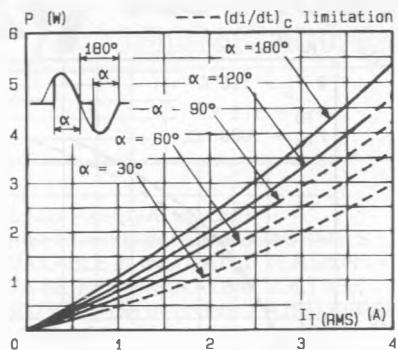


Fig.1 - Maximum mean power dissipation versus RMS on-state current ( $F = 60$  Hz).

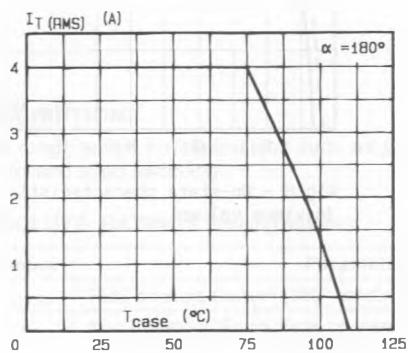


Fig.3 - RMS on-state current versus case temperature.

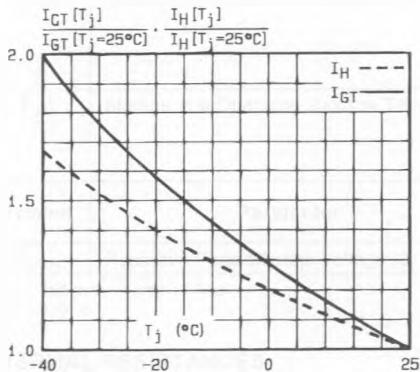


Fig.5 - Relative variation of gate trigger current and holding current versus junction temperature.

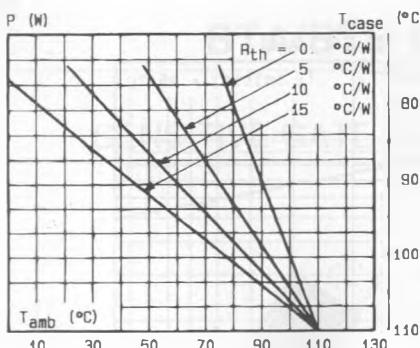


Fig.2 - Correlation between maximum mean power dissipation and maximum allowable temperatures ( $T_{amb}$  and  $T_{case}$ ) for different thermal resistances heatsink + contact.

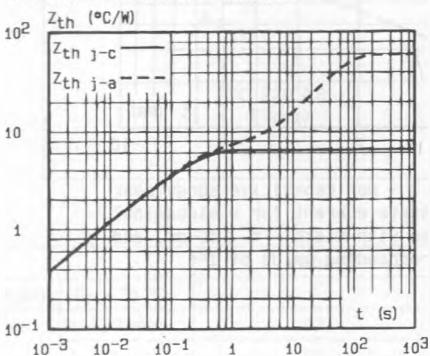


Fig.4 - Thermal transient impedance junction to case and junction to ambient versus pulse duration.

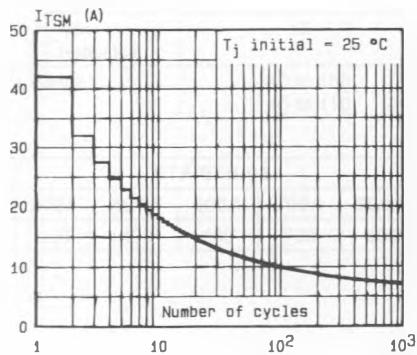


Fig.6 - Non repetitive surge peak on-state current versus number of cycles.

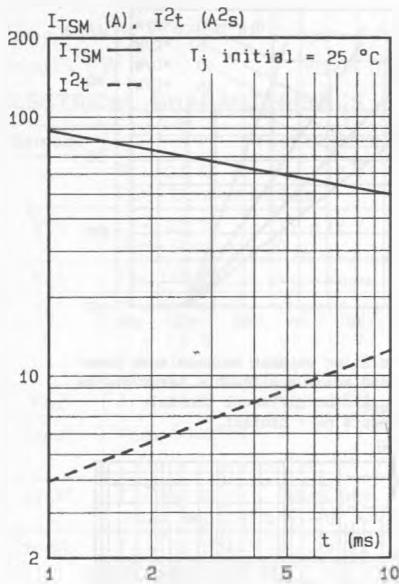


Fig.7 - Non repetitive surge peak on-state current for a sinusoidal pulse with width :  $t \leq 10$  ms, and corresponding value of  $I^2t$ .

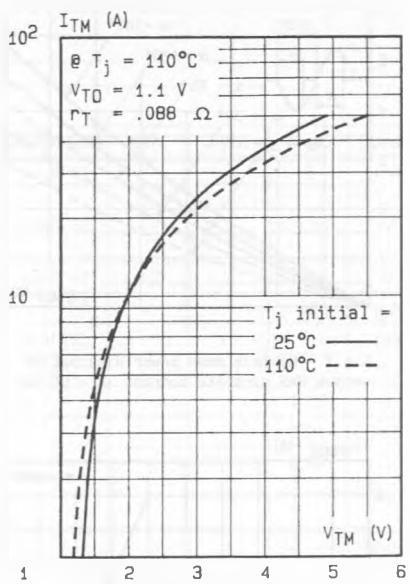


Fig.8 - On-state characteristics (maximum values).